

## United States Patent and Trademark Office

<u>I</u>V

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450

Alexand www.us	ia, Virginia 22313-14	50
	w.gov	

FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
John Robertson Tower	SAR 14108	9999	
	EXAMINER		
	GEBREMARIA	GEBREMARIAM, SAMUEL A	
	ARTUNIT	PAPER NUMBER	
		4	
		John Robertson Tower SAR 14108  EXAM	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)
Advisory Action	09/942,835	TOWER ET AL.
Advisory Addon	Examiner	Art Unit
	Samuel A Gebremariam	2811
The MAILING DATE of this communication appe	ars on the cover sheet with the c	orrespondence address
THE REPLY FILED 17 June 2004 FAILS TO PLACE TH Therefore, further action by the applicant is required to average final rejection under 37 CFR 1.113 may only be either: (1) condition for allowance; (2) a timely filed Notice of Appeal Examination (RCE) in compliance with 37 CFR 1.114.	oid abandonment of this applica a timely filed amendment which	ation. A proper reply to a n places the application in
PERIOD FOR RE	PLY [check either a) or b)]	
<ul> <li>a)</li></ul>	Advisory Action, or (2) the date set forth ater than SIX MONTHS from the mailing FILED WITHIN TWO MONTHS OF TH	g date of the final rejection. HE FINAL REJECTION. See MPEP
Extensions of time may be obtained under 37 CFR 1.136(a). The fee have been filed is the date for purposes of determining the period of fee under 37 CFR 1.17(a) is calculated from: (1) the expiration date of (2) as set forth in (b) above, if checked. Any reply received by the Offic timely filed, may reduce any earned patent term adjustment. See 37 C	of extension and the corresponding amo the shortened statutory period for reply the later than three months after the mail	ount of the fee. The appropriate extension originally set in the final Office action; or
1. A Notice of Appeal was filed on Appellant's 37 CFR 1.192(a), or any extension thereof (37 CFF		
2. $\boxtimes$ The proposed amendment(s) will not be entered be	ecause:	
(a) X they raise new issues that would require further	er consideration and/or search (s	see NOTE below);
(b) they raise the issue of new matter (see Note b	elow);	
<ul><li>(c)  they are not deemed to place the application in issues for appeal; and/or</li></ul>	n better form for appeal by mate	rially reducing or simplifying the
(d)  they present additional claims without canceli	ng a corresponding number of fi	inally rejected claims.
NOTE: <u>See Continuation Sheet</u> .		
3. Applicant's reply has overcome the following reject		
4. Newly proposed or amended claim(s) would canceling the non-allowable claim(s).	be allowable if submitted in a se	eparate, timely filed amendment
5. ☑ The a) ☐ affidavit, b) ☐ exhibit, or c) ☑ request for application in condition for allowance because: Se		dered but does NOT place the
6. The affidavit or exhibit will NOT be considered bec raised by the Examiner in the final rejection.	ause it is not directed SOLELY t	o issues which were newly
7. For purposes of Appeal, the proposed amendment explanation of how the new or amended claims we		
The status of the claim(s) is (or will be) as follows:		
Claim(s) allowed:		
Claim(s) objected to:		
Claim(s) rejected: <u>1,2,7-11,13-18,20,21,31 and 32</u> .		
Claim(s) withdrawn from consideration:		
8. The drawing correction filed on is a) app	roved or b) disapproved by t	he Examiner.
9. Note the attached Information Disclosure Statemen	nt(s)( PTO-1449) Paper No(s)/_	
10. Other:		
	SUPER	EDDIE LEE VISORY PATENT EXAMINER

TECHNOLOGY CENTER 2800

Continuation of 2. NOTE: the proposed limitation of preventing charge barriers from interfereing with charge transfer between adjacent gate electrode as recited in claim 7 warants further consideration and/or search.

Continuation of 5. does NOT place the application in condition for allowance because: Applicant argues the claimed limitation of "apparatus for stabilizing the inter-electrode gap selected from a group consisting of: a semiconductor region of the first conductivity type but having a different dopant concentration than the substrate, in the inter-electrode gap; and means for applying respective bias potentials to the at least two gate electrodes, the bias potentials being sufficient to cause a fringing field to extend across the inter-electrode gap from at least one of the at least two gate electrodes" as recited in claims 1, 11 and 18 constitute proper Markush group. The examiner finds applicants argument persuasive. Therefore the examiner removes the 112 rejection. However claim 1 is anticpated by Fujii as indicated in the final rejection. Claims 11 and 18 are similar to claim 1, except for the limitation of a semiconductor layer of a first conductivity formed on the substrate. This limitation is clearly shown in figures 8 and 9 (conductivity type (10) and dielectric layer (12)). Therefore the examiner maintains the position that the claimed inventions are prima facie obvious over Fujii. With respect to claim 20 the examiner maintains the position that back illuminated imagers are conventional in the art. Furthermore Savoye US patent No. 6,489,992 is cited herein only for purposes of evidence that "back illuminated imager" is well known in the art.